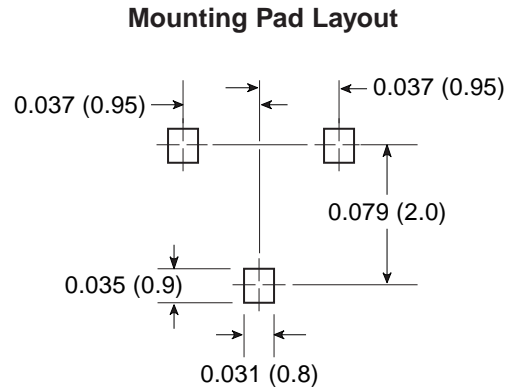
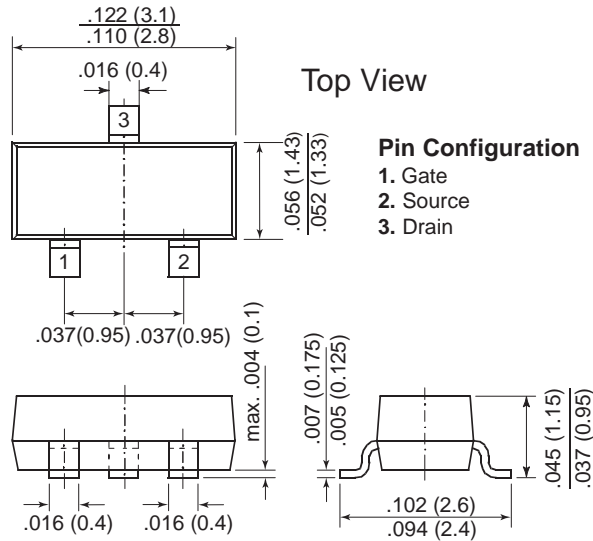


DMOS Transistors (N-Channel)



TO-263AB (SOT-23)



Dimensions in inches and (millimeters)

Features

- High input impedance
- High-speed switching
- No minority carrier storage time
- CMOS logic compatible input
- No thermal runaway
- No secondary breakdown

Mechanical Data

Case: SOT-23 Plastic Package

Weight: approx. 0.008g

Packaging Codes/Options:

- E6/Bulk- 5K per container, 20K/box
- E7/4K per Ammo tape, 20K/box

Maximum Ratings and Thermal Characteristics (T_A = 25°C unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|---------------------------------------------------|-------------------|----------------------|------|
| Drain-Source Voltage | V _{DSS} | 60 | V |
| Drain-Gate Voltage | V _{DGS} | 60 | V |
| Gate-Source-Voltage (pulsed) | V _{GS} | ±20 | V |
| Drain Current (continuous) | I _D | 250 | mA |
| Power Dissipation at T _{SB} = 50°C | P _{tot} | 0.310 ⁽¹⁾ | W |
| Thermal Resistance Junction to Substrate Backside | R _{thSB} | 320 ⁽¹⁾ | °C/W |
| Thermal Resistance Junction to Ambient Air | R _{thJA} | 450 ⁽¹⁾ | °C/W |
| Junction Temperature | T _j | 150 | °C |
| Storage Temperature Range | T _s | -65 to +150 | °C |

Note:

(1) Ceramic Substrate 0.7 mm; 2.5 cm² area.

DMOS Transistors (N-Channel)

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise noted)

| Parameter | Symbol | Test Condition | Min | Typ | Max | Unit |
|----------------------------------|---------------|------------------------------------------------------------|-----|-----|-----|---------------|
| Drain-Source Breakdown Voltage | $V_{(BR)DSS}$ | $I_D = 100\mu\text{A}, V_{GS} = 0$ | 60 | 80 | — | V |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{GS} = V_{DS}, I_D = 1\text{mA}$ | 1.0 | 2.0 | 3.0 | |
| Gate-Body Leakage Current | I_{GSS} | $V_{GS} = 15\text{V}, V_{DS} = 0\text{V}$ | — | — | 10 | nA |
| Drain Cutoff Current | I_{DSS} | $V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ | — | — | 0.5 | μA |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = 10\text{V}, I_D = 200\text{mA}$ | — | 3.5 | 5.0 | Ω |
| Forward Transconductance | g_m | $V_{DS} = 10\text{V}, I_D = 200\text{mA}, f = 1\text{MHz}$ | — | 200 | — | mS |
| Input Capacitance | C_{iss} | $V_{DS} = 10\text{V}, V_{GS} = 0, f = 1\text{MHz}$ | — | 30 | — | pF |
| Turn-On Time | t_{on} | $V_{GS} = 10\text{V}, V_{DS} = 10\text{V}$ | — | 5 | — | ns |
| Turn-Off Time | t_{off} | $R_D = 100\Omega$ | — | 25 | — | |

Note:

(1) Device on fiberglass substrate, see layout

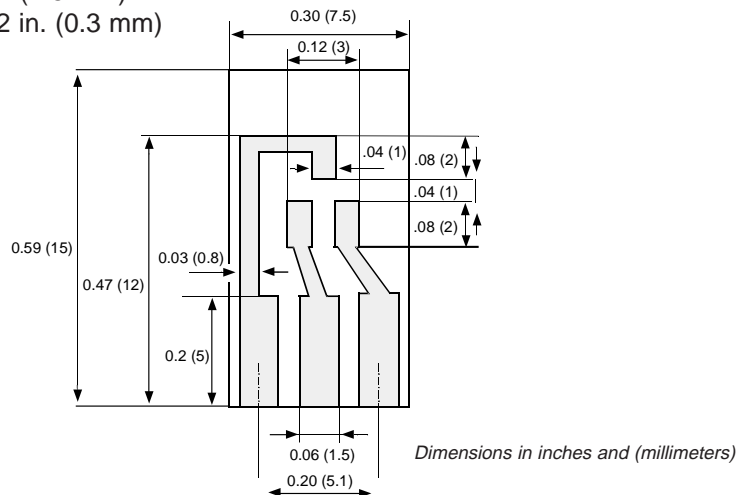
Inverse Diode

| Parameter | Symbol | Test Condition | Value | Unit |
|-----------------------------------|--------|-----------------------------------------------------------------|-------|------|
| Max. Forward Current (continuous) | I_F | $T_{amb} = 25^\circ\text{C}$ | 0.3 | A |
| Forward Voltage Drop (typ.) | V_F | $V_{GS} = 0\text{V}, I_F = 0.3\text{A}, T_J = 25^\circ\text{C}$ | 0.85 | V |

Layout for R_{thJA} test

Thickness: Fiberglass 0.059 in. (1.5 mm)

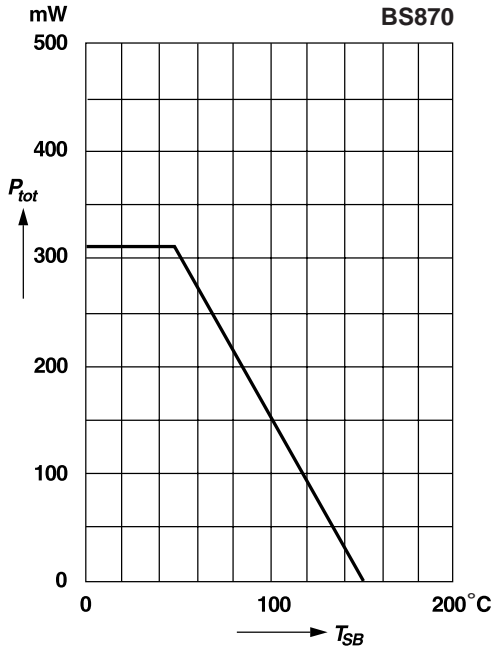
Copper leads 0.012 in. (0.3 mm)



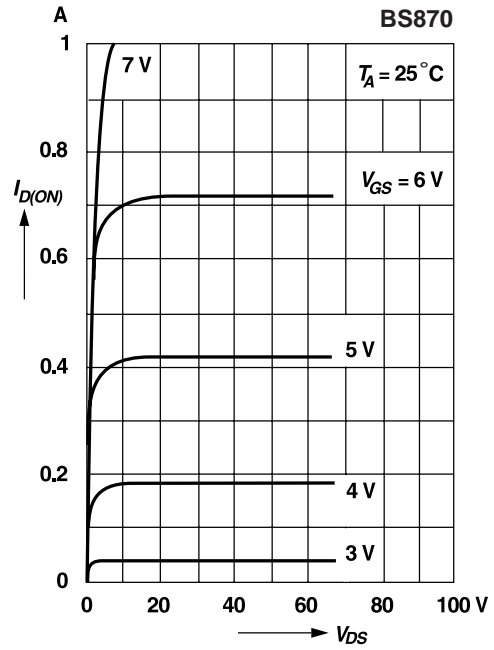
DMOS Transistors (N-Channel)

Ratings and Characteristic Curves (T_A = 25°C unless otherwise noted)

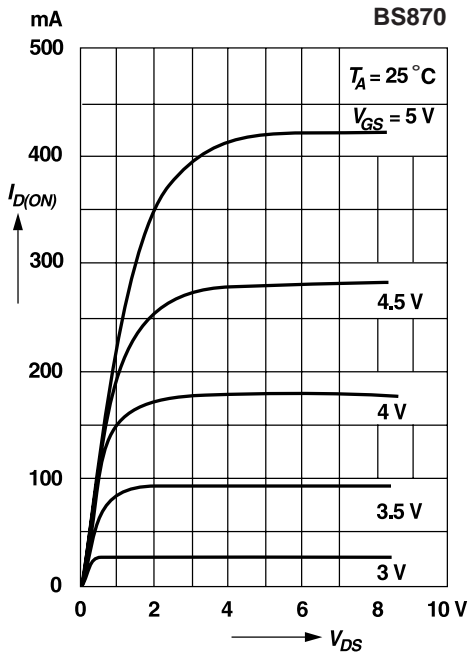
Admissible power dissipation versus temperature of substrate backside
 Device on fiberglass substrate, see layout



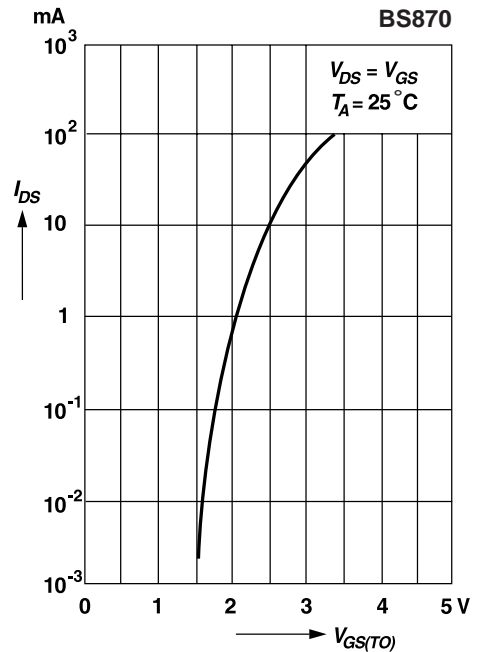
Output characteristics
 Pulse test width 80 ms; pulse duty factor 1%.



Saturation characteristics
 Pulse test width 80 ms; pulse duty factor 1%.



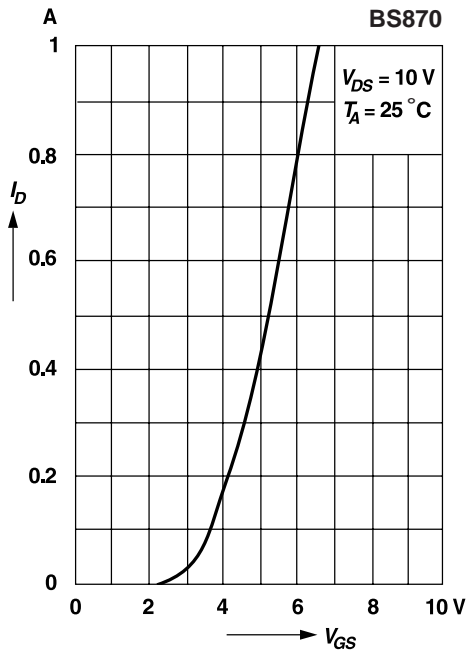
Drain-source current versus gate threshold voltage



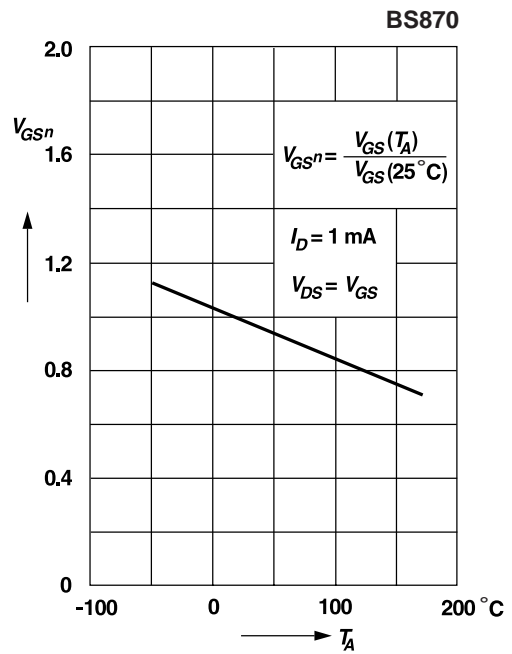
DMOS Transistors (N-Channel)

Ratings and Characteristic Curves (T_A = 25°C unless otherwise noted)

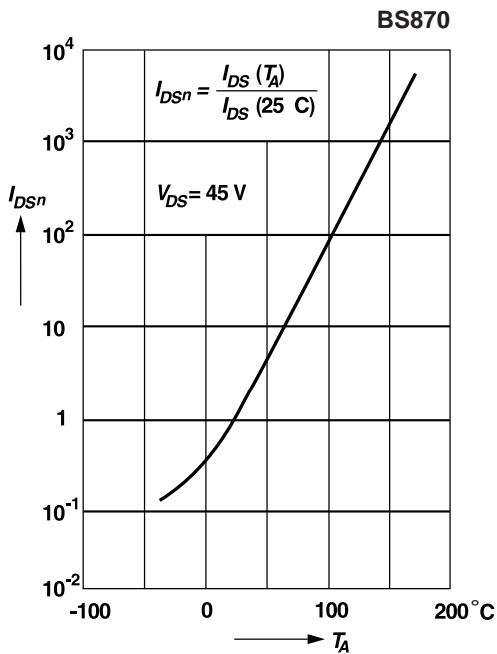
Drain current versus gate-source voltage
Pulse test width 80 ms; pulse duty factor 1%.



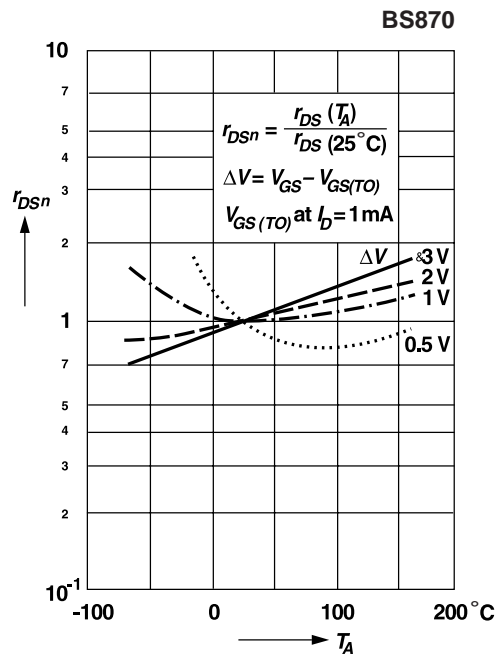
Normalized gate-source voltage versus temperature



Normalized drain-source current versus temperature



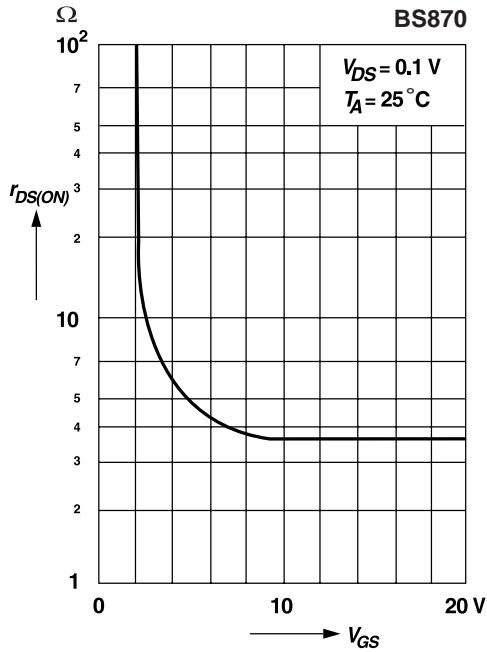
Normalized drain-source resistance versus temperature



DMOS Transistors (N-Channel)

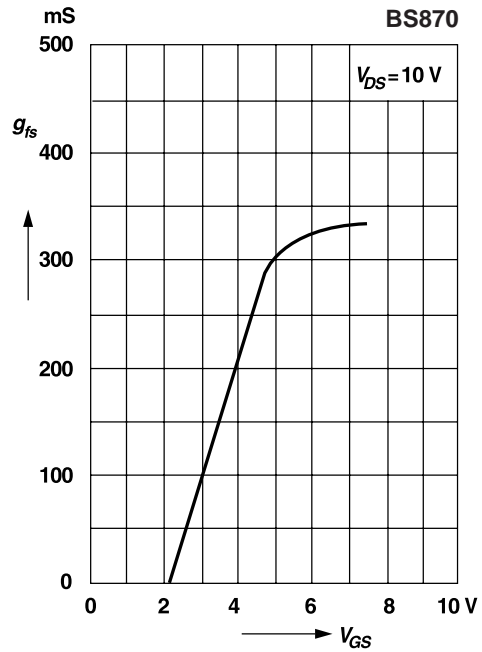
Ratings and Characteristic Curves (T_A = 25°C unless otherwise noted)

Drain-source resistance versus gate-source voltage



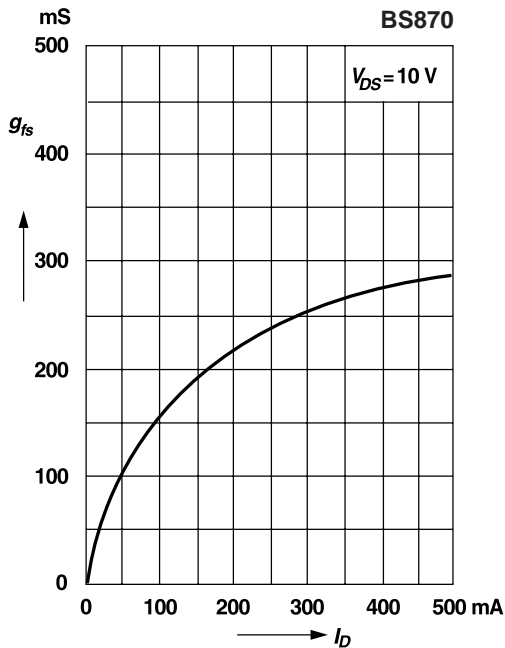
Transconductance versus gate-source voltage

Pulse test width 80 ms; pulse duty factor 1%



Transconductance versus drain current

Pulse test width 80 ms; pulse duty factor 1%



Capacitance versus drain-source voltage

